

**Search Notes**

Application/Control No.

10/522,231

Examiner

Ahshik Kim

Applicant(s)/Patent under  
Reexamination

MAYER ET AL.

Art Unit

2876

**SEARCHED**

Class	Subclass	Date	Examiner
235	454	7/25/2007	AK
	491		
	462.41		
	462.42		
	457		
356	71		
	73.1		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	7/25/2007	AK